

Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{rr})
- Halogen free, RoHS compliant

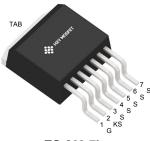
Benefits

- · Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

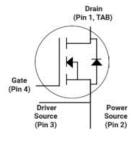
Applications

- Renewable energy
- EV battery chargers
- High voltage DC/DC converters
- Switch Mode Power Supplies





TO-263-7L Package



Ordering Part Number	Package	Marking		
SCT3040KW7TL	TO-263-7L	HC1M40120J		

Maximum Ratings ($T_c = 25$ °C unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	1200	V
Continuous drain current			
T _C = 25°C , V _{GS} = 15V	I _D	65	Α
$T_{C} = 100^{\circ}C, V_{GS} = 15V$		46	
Pulsed drain current (T_c = 25°C, t_p limited by T_{jmax})	I _{D pulse}	120	A
Gate-Source voltage	V _{GS}	-4/+18	V
Gate-Source voltage(Absolute maximum values)	V _{GSmax}	-8/+22	V
Power dissipation (T _C = 25°C)	P _{tot}	326	W
Operating junction and storage temperature	T _j , T _{stg}	-40+175	°C

•Example of acceptable V_{GS} waveform





Thermal Resistance

Parameter	Symbol	Value	Unit	
Thermal resistance, junction – case. Max	R _{thJC}	0.46	°C/W	
Thermal resistance, junction – ambient. Max	R _{thJA}	40	C/VV	

Electrical Characteristics (at Tj = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			11	Toot Condition
Parameter		min.	typ.	max.	Unit	Test Condition
Static Characteristics						
Drain-source breakdown voltage	BV _{DSS}	1200	-	-	V	V _{GS} =0V, I _D =100uA
Gate threshold voltage	V _{GS(th)}	2.2	3	4	V	$V_{DS}=V_{GS}$, $I_{D}=10mA$
						V _{DS} =1200V,V _{GS} =0V
Zero gate voltage drain current	I _{DSS}	-	1	20	μA	T _C =25°C
		-	5	-		T _C =175°C
Gate-source leakage current	I _{GSS}	-		100	nA	V _{GS} =18V,V _{DS} =0V
						V _{GS} =15V,
Drain-source on-state resistance	R _{DS(on)}	-	40	52	mΩ	I _D =33.3A, T _J =25°C
		-	62	-		T _J =175°C
						V _{GS} =18V,
Drain-source on-state resistance	$R_{DS(on)}$	-	32	40	mΩ	I _D =33.3A, T _J =25°C
		-	59	-		T _J =175°C
Transconductance	g _{fs}	-	20	-	S	V _{DS} =20V,I _D =33.3A



Dynamic Characteristics

Input Capacitance	C _{iss}	-	2766	-		V _{DS} = 1000V V _{GS} = 0V
Output Capacitance	C _{oss}	-	125	-	рF	V _{GS} – 0V T _J = 25°C
Reverse Transfer Capacitance	C _{rss}	-	14	-	nC	$V_{AC} = 25mV$ f = 1MHz $V_{DS} = 800V$ $V_{GS} = 0/15V$ $I_{D} = 33.3A$
Gate Total Charge	Q_G	-	112	-		
Gate-Source charge	Q _{gs}	-	28	-		
Gate-Drain charge	Q _{gd}	-	51	-		
Turn-On Switching Energy	E _{ON}	-	701	-		$V_{DD} = 800V$ $V_{GS} = -4/+15V$ $I_{D} = 20A$ $R_{G} = 2.5\Omega$ L = 120uH
Turn-Off Switching Energy	E _{OFF}	-	79	-	μJ	
Turn-on delay time	t _{d(on)}	-	13.4	-		
Rise time	t _r	-	5.4	-	ns	
Turn-off delay time	t _{d(off)}	-	32	-		
Fall time	t _f	-	19	-		
Gate resistance	R _G	-	0.6	-	Ω	V _{AC} = 25mV, f=1MHz

Body Diode Characteristics

Parameter	Symbol	Value				T (0)	
		min.	typ.	max.	Unit	Test Condition	
Body Diode Forward Voltage	V _{SD}		5.3		v	V _{GS} =-4V,I _{SD} =20A, T _J =25°C	
			4.8			V _{GS} =-4V,I _{SD} =20A, T _J =175°C	
Body Diode Reverse Recovery Time	t _{rr}	-	55	-	ns	V _R = 800V I _D = 33.3A	
Body Diode Reverse Recovery Charge	Q _{rr}	-	288	-	nC	di/dt = 1070A/µS T _J = 25°C	



Typical Performance Characteristics

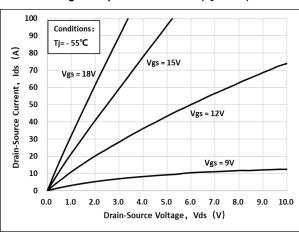


Fig 1. Output Characteristic (T_J=-55°C)

Fig 2. Output Characteristic (TJ=25°C)

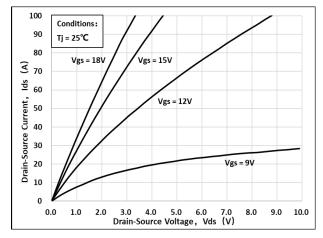
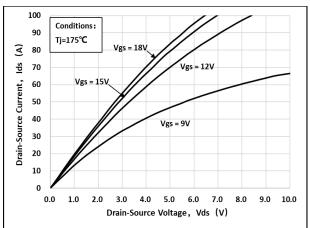
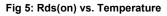


Fig 3. Output Characteristic (T_J=175°C)





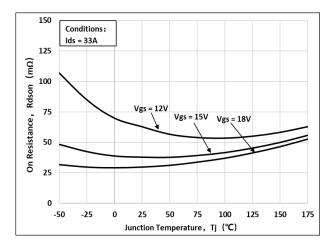
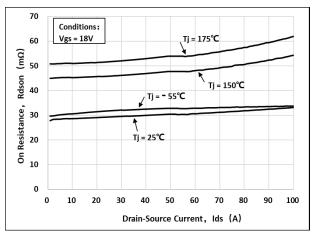


Fig 4: Rdson Vs Ids Characteristic





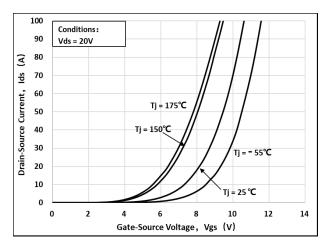




Fig 7: Body-diode Characteristic (T_J=-55°C)

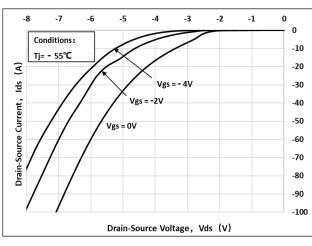


Fig 9: Body-diode Characteristic (T_J=175°C)

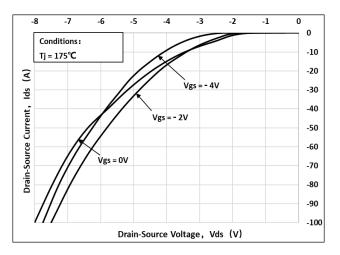
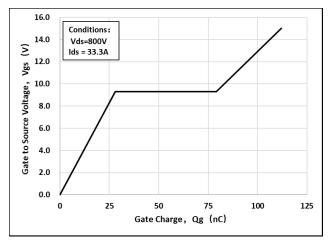


Fig 11: Gate Charge Characteristics



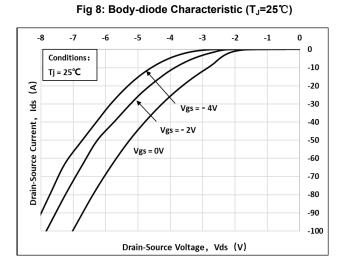
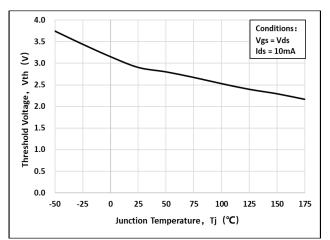
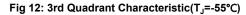
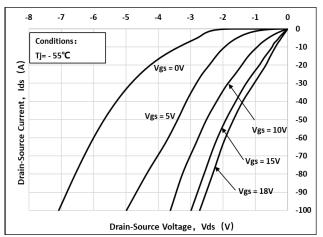


Fig 10: V_{TH} Vs T_J Temperature Characteristic









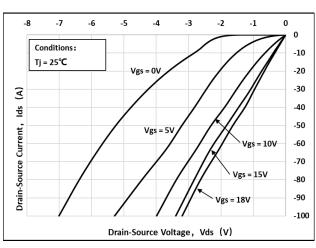


Fig 13: 3rd Quadrant Characteristic(T_J=25℃)

Fig 14: 3rd Quadrant Characteristic(TJ=175℃)

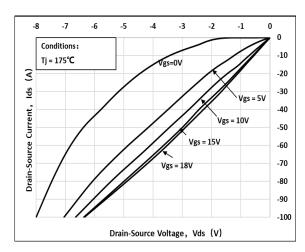


Fig 15: Capacitance Characteristic

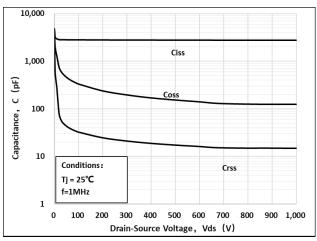


Fig 17: Transient Thermal Impedance

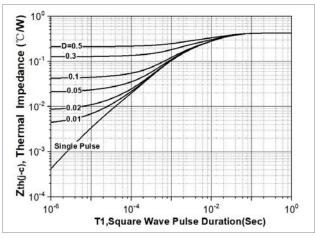
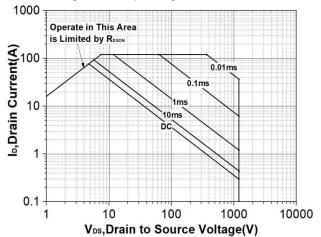


Fig 16: Safe Operating Area





Test Circuit & Waveform

Figure A. Definition of switching times

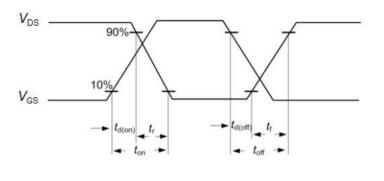


Figure B. Dynamic test circuit

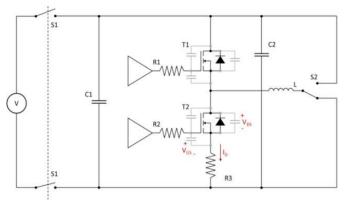
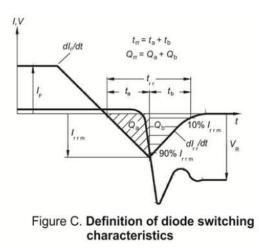
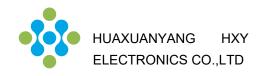


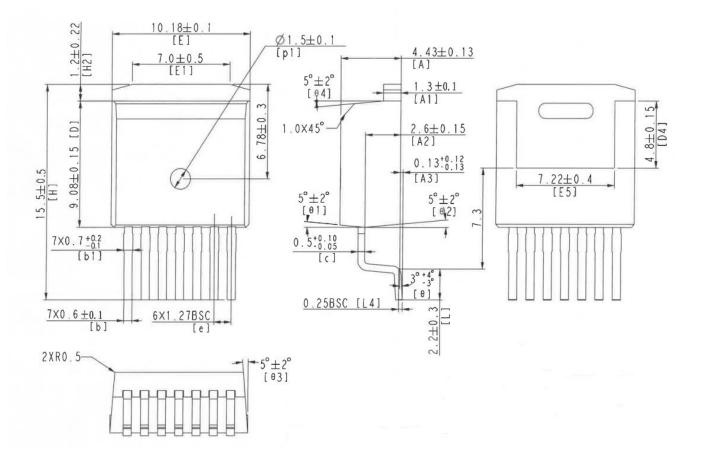
Figure C. Definition of body diode switching characteristics





Package Dimensions

Package TO-263-7L





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